

L Number	Hits	Search Text	DB	Time stamp
-	71	356/\$.cols. and (gate adj oxide)	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 14:04
-	59	356/\$.cols. and (gate adj oxide)	USFAT	2003/07/02 14:05
-	5	(gate adj oxide) and thickness and (high\$lk) and scatter\$	USFAT	2003/07/02 15:19
-	55	356/\$.cols. and (gate adj oxide) and thickness	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 15:25
-	231	halliyal-arvind singh-bhanwar supramanian-ramkumar).in.	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 15:26
-	18	halliyal-arvind singh-bhanwar subramanian-ramkumar).in. and (gate adj oxide) and thickness	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 15:26
-	22	356/\$.cols. and (gate adj oxide) and (thickness or uniform\$) and scatter\$	USFAT	2003/07/02 14:44
-	28	356/\$.cols. and (gate adj oxide) and (thickness or uniform\$) and scatter\$	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 16:56
-	9	("4710030" "4750822" "5298970" "5613526" "5798837" "5978074" "6060374" "6081330" "6381009").PN.	USFAT	2003/07/02 16:28
-	5	"4710030" "4750822" "5298970" "5613526" "5798837" "5978074" "6060374" "6081330" "6381009").PN. and scatter\$	USFAT	2003/07/02 16:29
-	0	("4710030" "4750822" "5298970" "5613526" "5798837" "5978074" "6060374" "6081330" "6381009").PN. and scatter\$ and (gate adj oxide)	USFAT	2003/07/02 16:29
-	32	356/\$.cols. and (gate adj oxide) and (thickness or uniform\$) and scatter\$	USFAT	2003/07/02 16:30
-	30	250/\$.cols. and (gate adj oxide) and (thickness or uniform\$) and scatter\$ not 356/\$.cols.	USFAT	2003/07/02 16:30
-	33	250/\$.cols. and (gate adj oxide) and (thickness or uniform\$) and scatter\$ not 356/\$.cols.	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 16:45
-	622	((gate adj oxide) with (thickness or uniform\$)) and scatter\$	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 12:10
-	19	((gate adj oxide) with (thickness or uniform\$)) and scatter\$.clm.	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 16:46
-	2	356/630-632.cols. and (gate adj oxide) and scatter\$	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 16:26
-	14	((gate adj oxide) with (thickness or uniform\$)).ab. and scatter\$	USFAT; US-PGFUE; EPO; JPO; DEFWENT; IBM_TDB	2003/07/02 12:38

-	0	("5860054" "6060374" "5880040").pn. and scatter\$	USPAT	2003/07/09 12:37
-	3	("5860054" "6060374" "5880040").pn.	USPAT	2003/07/09 12:11
-	9451	435/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/181).cccls. ((gate adj oxide) with thickness or uniform\$) and scatter\$ and nitrid\$ or nitrogen\$)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 12:41
-	9035	435/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/181).cccls. ((gate adj oxide) with thickness or uniform\$) and scatter\$.ab. and nitrid\$ or nitrogen\$)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 12:41
-	4	435/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/181).cccls. and ((gate adj oxide) with thickness or uniform\$) and scatter\$.ab. and nitrid\$ or nitrogen\$)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 12:44
-	1	435/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/181).cccls. and ((gate adj oxide) with thickness or uniform\$).ab. and scatter\$ and nitrid\$ or nitrogen\$)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 12:45
-	31	435/163,786,514,14-18,769 257/e21.193,e29.162 700/101,108,109 702/181).cccls. and ((gate adj oxide) with thickness or uniform\$) and scatter\$ and nitrid\$ or nitrogen\$)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/10 15:43
-	3	"6060433" "5904523" "6060374").pn.	USPAT	2003/07/09 15:12
-	2	"20020023900" "20030042432").pn.	US-PGPUB	2003/07/09 15:13
-	116	356/630-631.ccls. and (semiconductor or wafer) and scatter\$	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 16:26
-	10	356/630-631.ccls. and (semiconductor or wafer) and scatter\$.ab.	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/10 11:43
-	1	356/630-631.ccls. and (semiconductor or wafer) and (scatterometry with thickness)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 16:36
-	0	(scatterometry with nitrogen) and (semiconductor or wafer)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 16:36
-	0	(scatterometry with nitrogen)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 16:36
-	679	scatter\$ with nitrogen)	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 16:36
-	195	scatter\$ with nitrogen) and semiconductor or wafer or (gate adj oxide))	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 16:37
-	55	scatter\$ with nitrogen) and semiconductor or wafer or (gate adj oxide)) and scatter\$.ab.	USPAT; US-PGPUB; EPC; JPC; DEFWENT; IBM_TDB	2003/07/09 16:39

-	47	(scatter\$ with nitrogen) and (semiconductor or wafer or (gate adj oxide) and scatter\$.ab. not (electron near4 beam)	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/09 16:40
-	26	scatter\$ with nitrogen) and semiconductor or wafer or (gate adj oxide) and (scatter\$ and (nitrogen or nitride\$)).ab. not (electron near4 beam)	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/09 16:40
-	9	"5867276" "5877880" "5880833" "6081348" "6081334" "6141107" "6145564" "6383886" "6423977").PN.	USPAT	2003/07/10 11:16
-	1	"5867276" "5877880" "5880833" "6081348" "6081334" "6141107" "6145564" "6383886" "6423977").PN. and scatter\$.ab.	USPAT	2003/07/10 11:18
-	4	"4713642" "5164790" "5141369" "5803692").PN.	USPAT	2003/07/10 11:17
-	4	"5867276" "5877880" "5880833" "6081348" "6081334" "6141107" "6145564" "6383886" "6423977").PN. and scatteromets\$	USPAT	2003/07/10 11:18
-	17	356/630-632.ccls. and (semiconductor or wafer) and scatterom\$	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/10 12:01
-	16	356/630-632.ccls. and (semiconductor or wafer) and scatterom\$ not scatter\$.ab.	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/10 12:43
-	6	356/630.4,137.5.ccls. and (semiconductor or wafer) and scatterom\$ and thickness	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/10 14:17
-	7	250/589.27.ccls. and (semiconductor or wafer) and scatterom\$	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/10 11:55
-	1	250/589.27.ccls. and (semiconductor or wafer) and scatterom\$	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/10 11:55
-	21	356/630-632.ccls. and scatterom\$	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/10 12:01
-	10	356/630-632.ccls. and scatterom\$	USPAT	2003/07/10 12:01
-	154	356/630-632.ccls. and scatter\$	USPAT	2003/07/10 12:01
-	20	356/630-632.ccls. and scatter\$.ab.	USPAT	2003/07/10 12:02
-	20	356/630-632.ccls. and scatter\$.ab. and scatter\$	USPAT	2003/07/10 12:02
-	35	356 \$.ccls. and (semiconductor or wafer) and scatterom\$.ab.	USPAT; US-PGPUB; EPC; JPO; DEFWENT; IBM_TLB	2003/07/10 14:17
-	8	("5867276" "5877880" "5880833" "6100985" "6259521" "6266125" "6383886" "6424417").PN.	USPAT	2003/07/10 15:27
-	2	("5867276" "5877880" "5880833" "6100985" "6259521" "6266125" "6383886" "6424417").PN. and (nitrogen\$ or nitride\$)	USPAT	2003/07/10 15:27

-	61	(438/263,736,514,14-18,769 257/e21.193,e29.162 700/121,108,109 702/181).cls. and ((gate adj oxide) with cvd;	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 15:54
-	19	(438/263,736,514,14-18,769 257/e21.193,e29.162 700/121,108,109 702/181).cls. and (gate adj oxide).ab. and ((gate adj oxide) with cvd)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/07/10 15:57